Notice of References Cited Examiner Jacques M Saint-Surin Reexamination CHEN ET AL. Art Unit 2856 Page 1 of 1

Application/Control No.

Applicant(s)/Patent Under

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	Α	US-6,370,958	04-2002	Uhlig, Robert P	73/662
X	В	US-6,382,027	05-2002	Uhlig, Robert P.	73/579
X	С	US-6,314,813	11-2001	Uhlig, Robert P	73/664
X	D	US-6,145,382	11-2000	Nagasawa et al.	73/664
X	E	US-6,386,042	05-2002	Wortge et al.	73/657
X	F	US-6,257,063	07-2001	Uhlig, Robert P	73/579
X	G	US-6,014,899	01-2000	Uhlig et al.	73/664
X	Н	US-6,209,396	04-2001	Wortge et al.	73/657
X	Į	US-6,481,545	11-2002	Yano et al.	188/264G
X	j	US-5,456,339	10-1995	Zeng, Li J.	· 188/250E
X	К	US-5,887,686	03-1999	Tanaka et al.	188/250E
X	L	US-5,535,859	07-1996	Zeng, Li J.	188/250B
	М	US-			

FOREIGN PATENT DOCUMENTS

*	<u> 1</u>	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
,	N					
	0					
	Р					
	Q					
	R	·				
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	C	
	V	
	8	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.